Sheet 1 of 4	.41.					•				
	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) Date Submitted to PTO: January 5, 2004 *EXAMINER DOCUMENT NUMBER DATE NUMB	te.	ATTY DOCKET NO. 2003-1770	SERIAI NEW	ERIAL NO. NEW					
PA	TENT AN	ID TRADEMARK OFFIC	E	APPLICANT Kunihiko SAKURAI et al.						
	(Use sev	eral sheets if necessary)		FILING DATE January 5, 2004		GROUP				
			U.	S. PATENT DOCUMENTS						
			DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE			
b	AA	6,062,954	5/2000	Izumi						
1	ΑÐ	6,156,124	12/2000	Tobin						
	AC	5,897,426	4/1999	Somekh	_					
	AD	6,036,582	3/2000	Aizawa et al.						
	AE	6,180,020	1/2001	Moriyama et al.	ز	_				
	AF	5,655,954	8/1997	Oishi et al.						
	. AG	5,893,795	4/1999	Perlov et al.	. –		· · · · · · · · · · · · · · · · · · ·			
/	АH	5,830,045	11/1998	Togawa et al.	_					
AN	AI	5,738,574	4/1998	Tolles et al.						
			FOR	EIGN PATENT DOCUMENTS						
·		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO			
Δυ	AJ	9-232257	9/1997	JP ·						
	AK	97/10613	8/1997	wo		1-				
	AL	5-285807	11/1993	JP		_				
b	AM	197634	4/1908	Germany						
AU	AN	96/36459	11/1996	wo						
		OTHER	DOCUMENT(S)	ncluding Author, Title, Date, Perti	nent Pages, Etc.)					
Au	AO	U.S. Patent Application No. 09/301,718, filed April 4, 1999, entitled "Method and Apparatus For Polishing Workpiece", by Noburu SHIMIZU et al., located in Group Art Unit 3723.								
Do	АР	Kaitoh Tei et al., "Planarization of Device Wafer with Fixed Abrasive Particles (Second Report)" Planarization Working Characteristics with Fine Silica Grindstone, from the Japan Society for Precision Engineering.								
N	PΑ	U.S. Patent Applicat SAKURAI et al., loca		417, filed September 15, Art Unit 3723.	2000, entitled "	Polishing Appara	itus", by Kunihiko			
EXAMINER 4	Anthony Ofini DATE CONSIDERED 5/11/04									

'EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw tine through citation if not in conformance and not considered. Include copy of form with next communication to applicant.

Sheet 2 of 4									
FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S)				ATTY DOCKET NO. 2003-1770		ERIAL NO. IEW	. NO.		
				APPLICANT Kunihiko SAKURAI et al.					
1.3	(Use several sheets if necessary) Date Submitted to PTO: January 5, 2004			FILING DATE January 5, 2004		GROUP	GROUP		
			U.	S. PATENT DOCUMENTS					
'EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLAS	S SUBCLASS	FILING DATE IF APPROPRIATE		
AD	AA	5,679,059	10/1997	Nishi et al.	_	`			
) .	АВ	4,141,180	2/1979	Gill, Jr. et al.		- \	·		
	AC	5,827,110	10/1998	Yajima et al.					
	AD	5,232,875	8/1993	Tuttle et al.	_				
	AE	5,649,854	7/1997	Gill, Jr.					
	AF	5,562,524	10/1996	Gill, Jr.					
	AG	5,329,732	7/1994	Karlsrud et al.		_	116		
	АН	5,554,064	9/1996	Brievogel et al.					
Do	AI	5,885,138	3/1999	Okumura et al.					
			FORE	EIGN PATENT DOCUMENTS					
		DOCUMENT NUMBER	DATE	COUNTRY	CLAS	S SUBCLASS	TRANSLATION YES NO		
DO	AJ	82/03038	9/1982	wo	_				
	AK	874 309 A1	10/1998	Europe					
	AL	9-232257	9/1997	JP	-				
6	AM	7-135192	5/1995	JP		_ ^			
A	AN	8-64562	3/1996	JP					
	-	OTHE	R DOCUMENT(S)	Including Author, Title, Date, Pertin	ent Pages, E	(c.)			
O	AO	U.S. Patent Applica KATSUOKA et al., i	ition No. 09/341 located in Grou	1,882, filed September 8, 19 p Art Unit 3723.	999, entitle	ed "Polishing Appara	atus", by Seiji		
to	AP U.S. Patent Application No. 09/518,958, filed March 3, 2000, entitled "Polishing Apparatus", by Kunihiko SAKURAI et al., located in Group Art Unit 3723, a C-I-P of application Serial No. 09/476,905, filed January 3, 200								
	AQ								
EXAMINER	A.	othony O	jinj	DATE CONSIDER	ED	5/11/04			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of form with next communication to applicant.

Sheet 3 of 4					~				
FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S)				ATTY DOCKET NO. SERIAL NEW			NO.		
				APPLICANT Kunihiko SAKURAI et al.					
	(Use seve	eral sheets if necessary) ed to PTO: January 5, 20		FILING DATE January 5, 2004			GROUP		
			. <u> </u>	S. PATENT DOCUMENTS					
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CL	ASS	SUBCLASS	FILING DA	
Ao	AA	5,616,063	4/1997	Okumura et al.	-		^		
	АВ	3,906,678	9/1975	Roth					
	AC	3,913,271	10/1975	Boettcher		-	-		
	AD	5,718,618	2/1998	Guckel et al.		····	_	•	
	AE	5,989,107	11/1999	Shimizu et al.	_	-			
	AF	5,618,227	4/1997	Tsutsumi et al.	_	•			
	AG	3,659,386	5/1972	Goetz et al.	_	_			
4	АН	4,680,893	7/1987	Cronkhite et al.					
10	AI	5,551,986	9/1996	Jain			12		
			FOR	EIGN PATENT DOCUMENTS					
		DOCUMENT NUMBER	DATE	COUNTRY	Cr	ASS	SUBCLASS	TRANSL/ YES	NO NO
A	AJ	5-285807	11/1993	JP			-		
,	AK	807 492 A2	11/1997	Europe			. 7		
	AL	10-256201	9/1998	JР			-		
4	AM	5-74749	3/1993	JP			`		
Au	AN	2-208931	8/1990	JP					
	,	OTHER	R DOCUMENT(S)	Including Author, Title, Date, Pertind	ent Pages	, Etc.)			
	AO							•	
	АР								
	AQ								
EVALUED	Ant	hony Ojiv	^	DATE CONSIDER	ED	.5	11/04	•	
EXAMINER	7 7 /		1 7				1:11:11		

'EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of form with next communication to applicant.

Sheet 4 of 4										
FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE				ATTY DOCKET NO. 2003-1770				NO.		
PA	TENT AN	D TRADEMARK OFFIC	E	APPLICANT Kunihiko SAKURAI et al.						
Date	·	ral sheets if necessary) d to PTO: January 5, 20	004	FILING DATE January 5, 2004			GROUP			
			U.	S. PATENT DOCUMENTS						
'EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	c	LASS	SUBCLASS	FILING DA	TE IF	
Ao	AA	5,951,373	9/1999	Shendon et al.	-	-	-			
	AB	5,839,947	11/1998	Kimura et al.	_					
	AC	6,050,884	4/2000	Togawa et al.						
	AD	6,293,855	9/2001	Yoshida et al.	. -					
AU	AE	5,498,199	3/1996	Karlsrod et al.			_			
	AF									
	•		FOR	EIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATÉ	COUNTRY	CLASS		SUBCLASS	TRANSLATION YES NO		
AD	AG	4-69147	3/1992	JP	-		_			
	.AH	0 517 594	12/1992	Europe			_			
	AI	0 684 634	11/1995	Europe						
	AJ	2-267950	11/1990	JP						
	ÄK	64-42823	2/1989	JP						
	AL	0761387A1	3/1997	EP			_			
	АМ	0807492A2	11/1997	EP			_			
	AN	0928662A2	7/1999	EP	_					
A)_	AO	0793261A2	9/1997	EP	_	<u></u>				
		OTHER	DOCUMENT(S) (ncluding Author, Tille, Date, Pertin	ent Pages	, Elc.)				
	AP	,				•				
	AQ									
	1	A	•	T			5/11/	<u> </u>		
XAMINER 1	atho	nu Olin		DATE CONSIDER	EU		ן וין ט			

*EXAMINER: Initial If reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of form with next communication to applicant.